

Search Notes



Application/Control No.

10/824,429

Examiner

Mike Stahl

Applicant(s)/Patent under
Reexamination

NAKAMURA ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385 385	123-127, 141-143	2/05	MJS
372	6	"	"
359	341.1, 341.3	"	"
359	341.5	"	"
65	385, 390	"	"
501	64, 68	"	"

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST text search; IEEE online search	2/05	MJS